

ABSTRACT

A measurement device for a thin film provided with a transparent substrate comprises a light source (1), a collimator lens (2), a filter (3), a polarizer (4), a light splitting element (5), and an objective lens (7) along a light path propagation direction. The light splitting element (5) is connected to a flat-panel detector (11) and a processor (13). Light emitted by the light source (1) sequentially passes through the collimator lens (2), the filter (3), the polarizer (4), the light splitting element (5) and the objective lens (7), and then forms measuring light that enters a thin film provided with a transparent substrate; the objective lens (7) and the light splitting element (5) collect reflective light from the thin film provided with a transparent substrate, and the flat-panel detector (11) and the processor (13) measure a physical parameter of the thin film provided with a transparent substrate according to the collected reflective light. The measurement device also comprises a shielding diaphragm used for removing reflective light that is generated due to the transparent substrate during the measurement and that interferes with the measurement.